

Finland-Helsinki: Scanning electron microscopes

OJ S 220/2020 11/11/2020

Contract notice

Supplies

Legal Basis:

Directive 2014/24/EU

Section I: Contracting authority

I.1. Name and addresses

Official name: University of Helsinki

National registration number: 0313471-7

Postal address: PL 4 (yliopistonkatu 3), Helsingin yliopisto

Town: Helsinki

NUTS code: FI1B Helsinki-Uusimaa

Postal code: 00014

Country: Finland

E-mail: toni.wolanen@helsinki.fi**Internet address(es):**Main address: <https://www.helsinki.fi/fi>**I.3. Communication**

The procurement documents are available for unrestricted and full direct access, free of charge, at: <https://hanki.tarjouspalvelu.fi/hanki?id=319553&tpk=89594a35-4626-4427-8206-032228510f83>

Additional information can be obtained from the abovementioned address

Tenders or requests to participate must be submitted electronically via: <https://hanki.tarjouspalvelu.fi/hanki?id=319553&tpk=89594a35-4626-4427-8206-032228510f83>**I.4. Type of the contracting authority**

Other type: University

I.5. Main activity

Other activity: Research and education

Section II: Object

II.1. Scope of the procurement**II.1.1. Title**

Focused Ion Beam Scanning Electron Microscope (FIB-SEM) for Biological Specimens

II.1.2. Main CPV code

38511100 Scanning electron microscopes

II.1.3. Type of contract

Supplies

II.1.4. Short description

A high resolution field emission scanning electron microscope (SEM) equipped with a focused ion beam (FIB) for serial block face and section imaging of plastic embedded biological specimens.

II.1.5. Estimated total value

Value excluding VAT: 870 000,00 EUR

II.1.6. Information about lots

This contract is divided into lots: no

II.2. Description

II.2.3. Place of performance

NUTS code: FI1B Helsinki-Uusimaa

II.2.4. Description of the procurement

The instrument should meet the following specifications:

- field emission electron source
 - accelerating voltage stable at very low kV (~1-1.5 kV) and adjustable up to 30 kV
 - SEM resolution ≤ 1.6 nm at 1 kV
 - detectors should be optimized for low kV imaging of biological specimens, and should include at least in-lens SE, in-lens BSE, in-chamber SE and retractable solid state BSE
 - large chamber with a load lock for fast specimen exchange
 - compatible for imaging of poorly conductive biological specimens
 - multi-axial motorized stage
 - cameras to assist navigation on the sample
 - integrated plasma cleaner
 - cold trap
 - focused ion beam column equipped with a long-lifetime stable gallium source capable to produce adjustable current for fast/coarse or precise milling
 - automatic FIB source management and reheat routines
 - milling step of at least 5 nm in serial-section milling applications
 - two gas injection systems: platinum and carbon
 - computer(s), monitor(s) and software for the operation of the microscope:
 - to acquire large image rasters of a single field of view
 - automated 2D montaging and stitching
 - automated serial FIB milling and block face imaging of plastic embedded samples for volumeEM
 - correlation with light microscopy and other imaging modalities.
- (Software that requires computational time should be provided as both online and offline versions.)
- Application Programming Interface (API) to control the microscope using Python scripting
 - Side offers must be itemized separately and may include UPS, additional holders or detectors, micromanipulator and software for lamella preparation, software for array tomography, or any other beneficial appliances such as air compressor and separate cooling units.

II.2.5. Award criteria

Price is not the only award criterion and all criteria are stated only in the procurement documents

II.2.6. Estimated value

II.2.7. Duration of the contract, framework agreement or dynamic purchasing system

Duration in months: 12

This contract is subject to renewal: no

II.2.10. Information about variants

Variants will be accepted: no

II.2.11. Information about options

Options: yes

Description of options:

Optional maintenance agreement. Also UPS, additional holders or detectors, micromanipulator and software for lamella preparation, software for array tomography, or any other beneficial appliances such as air compressor and separate cooling units.

II.2.13. Information about European Union funds

The procurement is related to a project and/or programme financed by European Union funds:
no

II.2.14. Additional information

Section IV: Procedure

IV.1. Description

IV.1.1. Type of procedure

Open procedure

IV.1.3. Information about a framework agreement or a dynamic purchasing system

IV.1.8. Information about the Government Procurement Agreement (GPA)

The procurement is covered by the Government Procurement Agreement: yes

IV.2. Administrative information

IV.2.2. Time limit for receipt of tenders or requests to participate

Date: 07/12/2020 Local time: 14:00

IV.2.3. Estimated date of dispatch of invitations to tender or to participate to selected candidates

IV.2.4. Languages in which tenders or requests to participate may be submitted

English

IV.2.6. Minimum time frame during which the tenderer must maintain the tender

Duration in months: 3 (from the date stated for receipt of tender)

IV.2.7. Conditions for opening of tenders

Date: 07/12/2020 Local time: 14:01

Section VI: Complementary information

VI.1. Information about recurrence

This is a recurrent procurement: no

VI.2. Information about electronic workflows

Electronic invoicing will be accepted

VI.3. Additional information

VI.4. Procedures for review

VI.4.1. Review body

Official name: Markkinaoikeus

Postal address: Radanrakentajantie 5

Town: Helsinki

Postal code: 00520

Country: Finland

E-mail: markkinaoikeus@oikeus.fi

Telephone: +358 295643300

Internet address: <http://www.oikeus.fi/markkinaoikeus>

VI.5. Date of dispatch of this notice

06/11/2020